REMARKS

In response to the Board of Appeals decision dated March 17, 2011, Applicants are filing this request for continued examination in which the mirrored surface is limited to a silicon wafer on which a tantalum nitride film is formed. Support for this amendment is found in paragraph [0032] of the In the Board's decision, the Board stated that specification. the evidence of unobvious results is not commensurate in scope with the claims and that only a silicon wafer having a tantalum nitride film was tested. Accordingly, the currently presented claims have been limited to this feature. A person of ordinary skill in the art would not come up with the present invention from the Kondo reference because Kondo fails to teach the use of a plating of a silicon wafer on which a tantalum nitride film is formed and there is no quarantee that the teaching of Imori, if applied to Kondo, would result in a successful plating operation. Favorable consideration of the present application is respectfully solicited.

Respectfully submitted,

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TFC/smd

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Encl: None

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